

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	150			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.187		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			82	mΩ	V _{GS} = 10V, I _D = 12A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
I _{DSS}	Drain to Source Leakage Current			25		$V V_{DS} = V_{GS}, I_D = 250\mu A$ $V_{DS} = 150V, V_{GS} = 0V$ $V_{DS} = 120V, V_{GS} = 0V, T_J = 125^{\circ}C$
	Drain-to-Source Leakage Current			250	μΑ	
I _{GSS}	Gate-to-Source Forward Leakage			100	A	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-100	nA	$V_{GS} = -20V$

Dynamic Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

Q_g	Total Gate Charge	 	95		I _D = 12A
Q_{gs}	Gate-to-Source Charge	 	11	nC	V _{DS} = 120V
Q_{gd}	Gate-to-Drain Charge	 	47		V _{GS} = 10V4
$t_{d(on)}$	Turn-On Delay Time	 9.6			$V_{DD} = 75V$
t_r	Rise Time	 32		no	I _D = 12A
$t_{d(off)}$	Turn-Off Delay Time	 49		ns	$R_G = 5.1\Omega$,
t _f	Fall Time	 38			$R_D = 5.9\Omega$, $\textcircled{4}$
L_D	Internal Drain Inductance	 4.5			Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance	 7.5			from package and center of die contact:
C _{iss}	Input Capacitance	 1300			$V_{GS} = 0V$
C _{oss}	Output Capacitance	 300		рF	$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance	 160			f = 1.0MHz, See Fig.5

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			21	١.	MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			84		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	٧	$T_J = 25^{\circ}C, I_S = 12A, V_{GS} = 0V \oplus$
t _{rr}	Reverse Recovery Time		174	260	ns	$T_J = 25^{\circ}C$, $I_F = 12A$
Q_{rr}	Reverse Recovery Charge		1.2	1.7	μC	di/dt = 100A/μs ④
t_{on}	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig.11)
- \odot Limited by T_{Jmax}, starting T_J = 25°C, L = 4.9mH, R_G = 25 Ω , I_{AS} = 12A. (See fig.12)
- $\label{eq:loss_def} \text{ } \text{ } I_{SD} \leq 12A, \text{ } \text{di/dt} \leq 140A/\mu\text{s}, \text{ } V_{DD} \leq V_{(BR)DSS}, \text{ } T_J \leq 175^{\circ}\text{C}.$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- S When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- © R_{θ} is measured at T_J of approximately 90°C



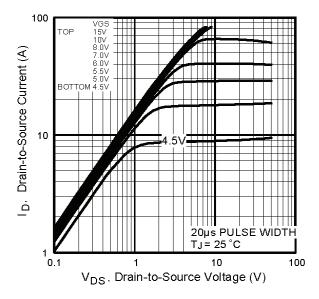


Fig. 1 Typical Output Characteristics

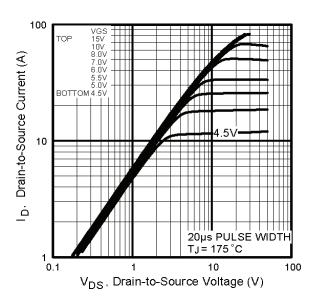


Fig. 2 Typical Output Characteristics

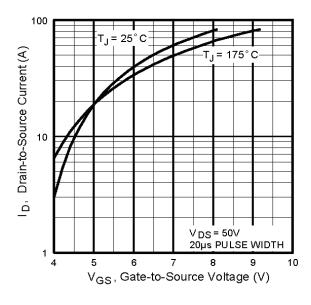


Fig. 3 Typical Transfer Characteristics

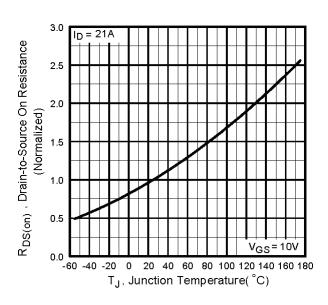


Fig. 4 Normalized On-Resistance vs. Temperature



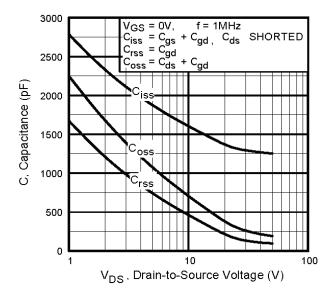


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

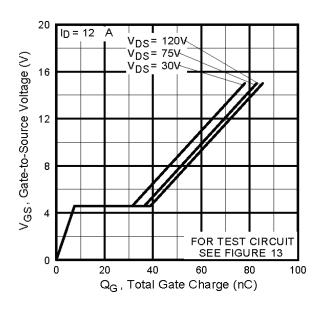


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

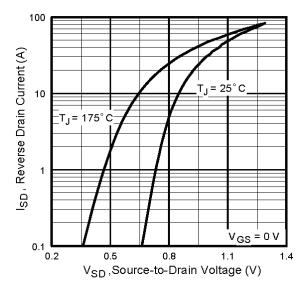


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

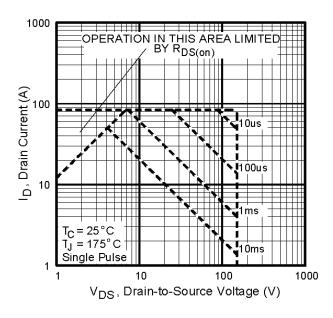


Fig 8. Maximum Safe Operating Area



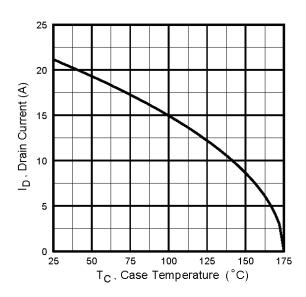


Fig 9. Maximum Drain Current vs. Case Temperature

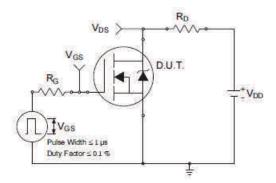


Fig 10a. Switching Time Test Circuit

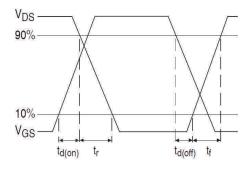


Fig 10b. Switching Time Waveforms

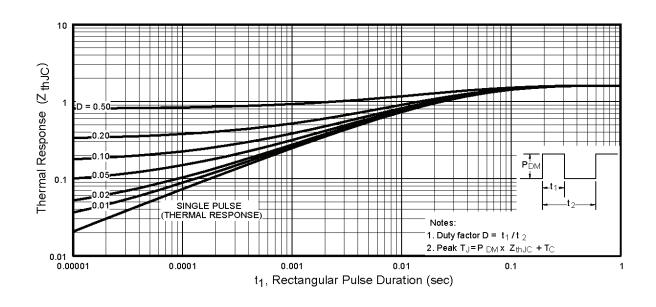


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



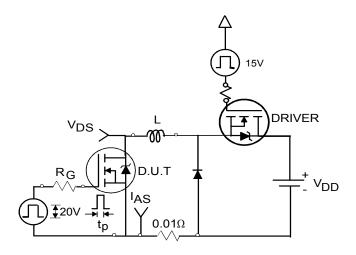


Fig 12a. Unclamped Inductive Test Circuit

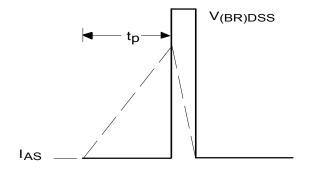


Fig 12b. Unclamped Inductive Waveforms

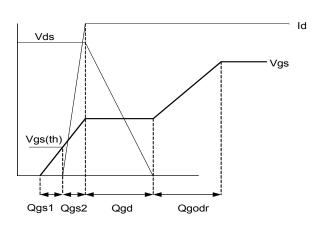


Fig 13a. Gate Charge Waveform

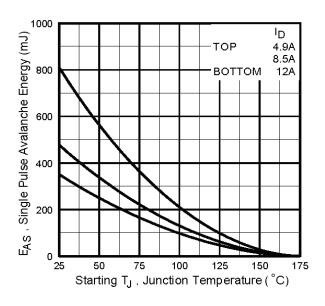


Fig 12c. Maximum Avalanche Energy vs. Drain Current

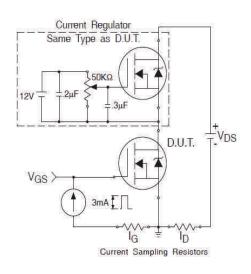
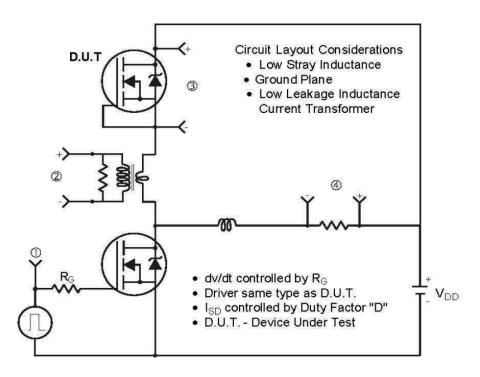


Fig 13b. Gate Charge Test Circuit

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Peak Diode Recovery dv/dt Test Circuit



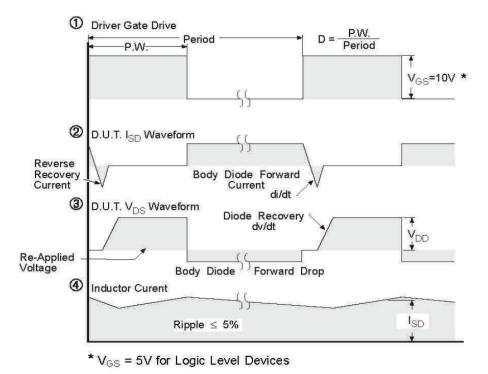
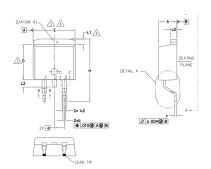
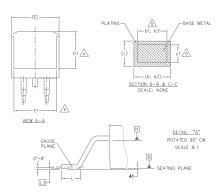


Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S	DIMENSIONS					
M B	MILLIM	ETERS	INC	INCHES		
0 L	MIN.	MAX.	MIN.	MAX.	O T E S	
А	4.06	4.83	.160	.190		
A1	0.00	0.254	.000	.010		
Ь	0.51	0.99	.020	.039		
ь1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
ь3	1,14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
с1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	_	.270	_	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	_	.245	_	4	
е	2.54	BSC	.100	BSC		
Н	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	_	1.68	_	.066	4	
L2	_	1.78	_	.070		
L3	0.25	BSC	.010	BSC		

LEAD ASSIGNMENTS

DIODES

1.— ANODE (TWO DIE) / OPEN (ONE DIE) 2, 4.— CATHODE 3.— ANODE

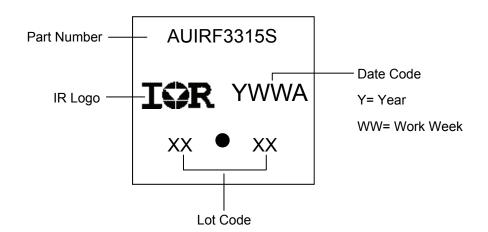
HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

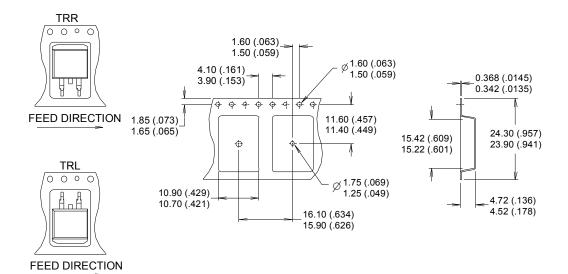
D²Pak (TO-263AB) Part Marking Information

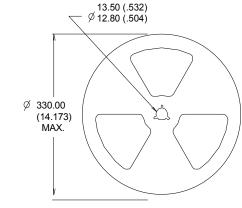


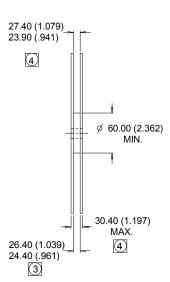
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







- NOTES:
- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

Qualification Level		Automotive (per AEC-Q101)					
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.					
Moisture Sensitivity Level		D ² -Pak MSL1					
	Machine Model		Class M4 (+/- 600V) [†]				
	Machine Model	AEC-Q101-002					
EGD	Human Rody Model	Class H1C (+/- 2000V) [†]					
ESD	Human Body Model	AEC-Q101-001					
	Charged Davies Medal	Class C5 (+/- 2000V) [†]					
	Charged Device Model	AEC-Q101-005					
RoHS Compliant		Yes					

[†] Highest passing voltage.

Revision History

Date	Comments			
11/13/2015	 Updated datasheet with corporate template Corrected ordering table on page 1. Corrected typo in test condition current from "43A" to "12A" for VSD and trr/Qrr on page 2. 			

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